



## Features

- Formerly J. W. Miller® model
- Shielded construction
- Unit height of 4.2 mm
- Inductance range: 0.15  $\mu$ H to 2.5  $\mu$ H
- Current up to 34 A
- RoHS compliant\*

## Applications

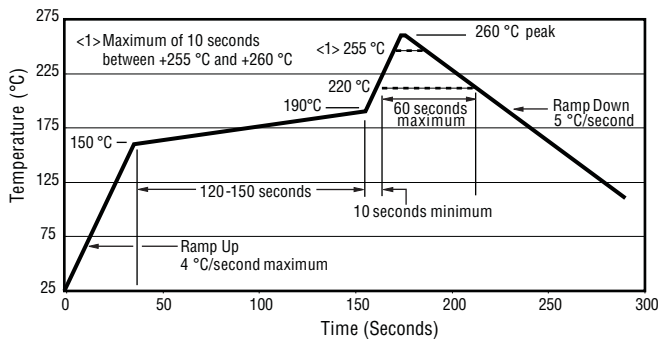
- Input/output of DC/DC converters
- Power supplies for:
  - Portable communication equipment
  - Camcorders
  - LCD TVs
  - Car radios

# PM1038S Series - Shielded Power Inductors

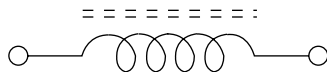
## Electrical Specifications

Bourns Part No.	Inductance L ( $\mu$ H)	I rms (A)	I sat (A)	DCR (m $\Omega$ ) max.
PM1038S-R15M-RC	0.15	34	40	1.3
PM1038S-R39M-RC	0.39	24	32	1.4
PM1038S-R50M-RC	0.50	23	32	1.9
PM1038S-R75M-RC	0.75	22	28	2.5
PM1038S-1R2M-RC	1.2	18	24	4.7
PM1038S-1R7M-RC	1.7	15	18	7.5
PM1038S-2R5M-RC	2.5	11.5	14	8.7

## Soldering Profile



## Electrical Schematic



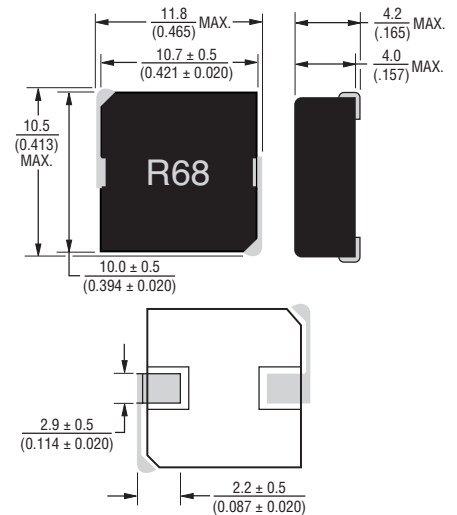
## General Specifications

Test Voltage .....0.25 V  
 Test Frequency ..... 100 KHz  
 Reflow Soldering ....230 °C; 50 sec max.  
 Operating Temperature  
 .....-55 °C to +150 °C  
 (Temperature rise included)  
 Storage Temperature .....  
 .....55 °C to +150 °C  
 Resistance to Soldering Heat  
 ..... +260 °C for 10 sec.

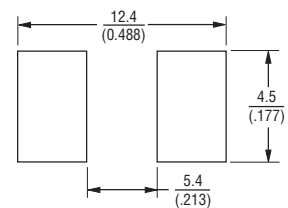
## Materials

Core .....Iron  
 Wire .....Enameled copper  
 Terminal ..... Cu/Sn  
 Rated Current .... Ind. drops 20 % at I sat  
 Temperature Rise .... 40 °C at rated I rms  
 Packaging ..... 800 pcs. per 13-inch reel

## Product Dimensions



## Recommended Layout



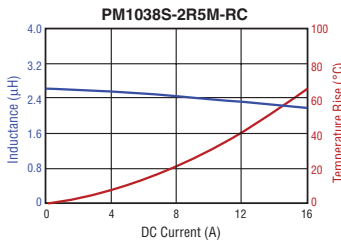
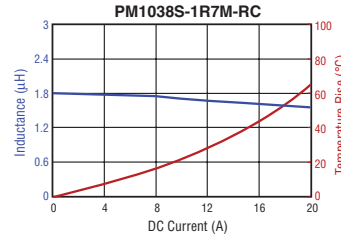
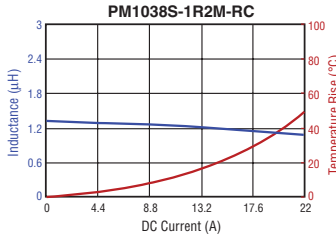
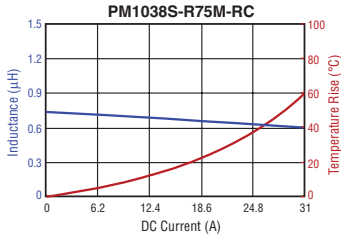
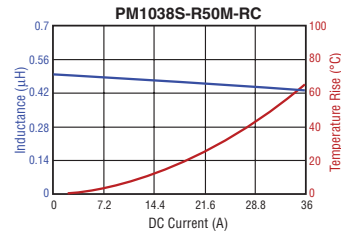
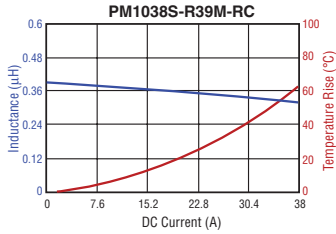
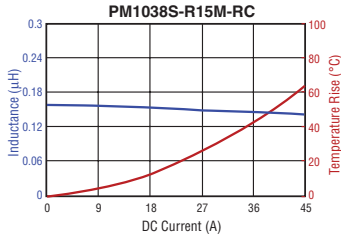
DIMENSIONS:  $\frac{\text{MM}}{\text{(INCHES)}}$

\*RoHS Directive 2002/95/EC Jan. 27, 2003 including annex and RoHS Recast 2011/65/EU June 8, 2011. Specifications are subject to change without notice. Customers should verify actual device performance in their specific applications..

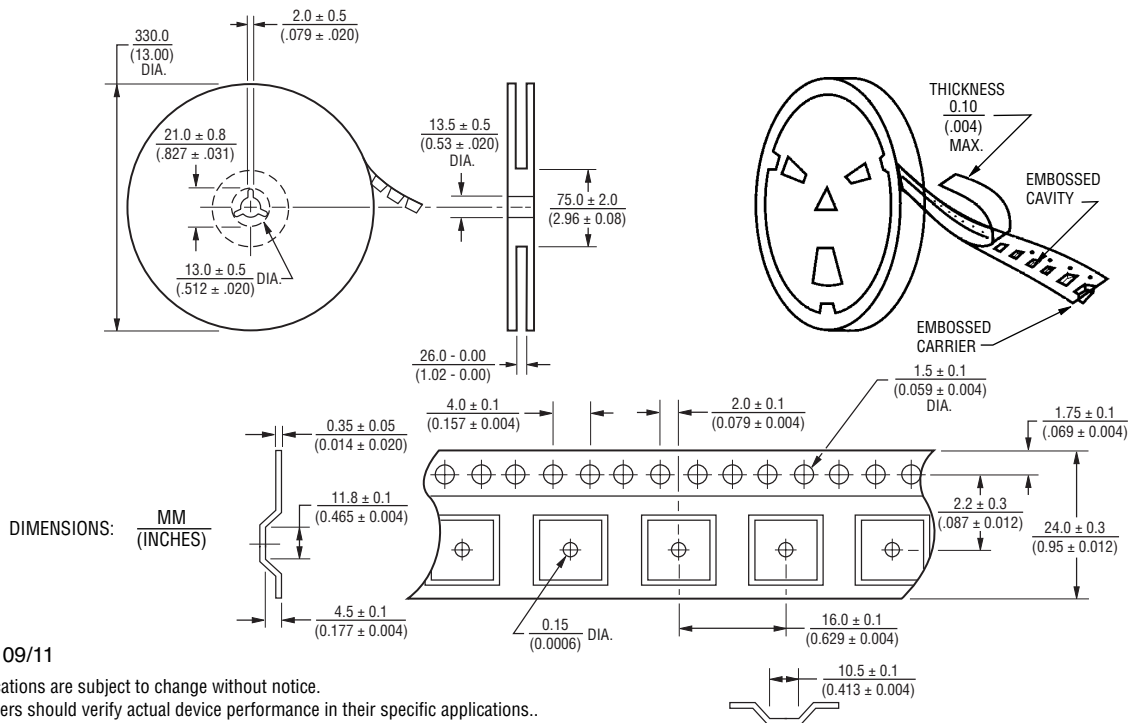
# PM1038S Series - Shielded Power Inductors



## L vs. I Charts



## Packaging Specifications



REV. 09/11

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